CLASSIFICATION

INFORMATION REPORT

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25X1	Research work in the Department for Crystal Academy Institute for Medicine and Biology	in Berlin-Buch has been		
25X1	hampered by the lack of an adequate method tensity of defraction spots (called "reflex	for determining the in- es" in Buch terminology)		
	this shortcoming is a	serious handican for		
25X1	crystal research analysis quite generally a prevails everywhere. So far, determination	nd		
25X1	be carried out by visual estimate, and this	carried out by visual estimate, and this procedure involved a gin of error of from five to thirty percent. While the relatively		
14,	small error of five percent is attainable a observation it gradually increases to thirt	t the beginning of an		
*	fatigue caused by long observation time.	y percent as a result of		
25X1 ² •	Which is supposed to aliminate t	development of a device		
1	which is supposed to eliminate to a great esubjective estimate. The device is called	"The Exposure Device for		
	* X-Ray Intensity Wedge" (Belichtungsgeraet keil); construction plans for the device we	re finished in late November		
25X1	1953. With the aid of this device and an e	valuation device,		
25X1	reduce the margin of error in the determina plus minus 0.5 percent.	tion of X-ray intensity to		
7 3.	- W			
	The Exposure device works in the following with a dark-slide (Kassette) into which the	X-ray film of a crystal is total		
duced	opened by means of two slides. The diaphrag	gms are exposed to an X-ray		
V, X	source after the slides are opened. By foto black "wedges" are produced on the X-ray fit position of the diaphragms is such that the film only takes place on the margin of the	ating the diaphragmatwo lm of the crystal. The blackening of the X-ray		
	picture of the crystal is not disturbed. The	ne black"wedges" are not		
V. X	uniformly black, but have different shades of the evaluation device yet to be developed compare the intensities of the diffraction signature.	t will be possible to		
	express them in exact figures. The dark-sli	ide is protected by a sheet		

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of lead against the X-ray source, so that direct exposure and exposure to scattered rays is impossible. The dimensions of the dark-slide have been selected so that films of several types of X-ray cameras, such as the Weissenberg and De Jong cameras, can be inserted.

25X1 4.	Construction of the Axposure Device has begue of the Institute for Medicine and Biology.	n in the research labaratory
25X1	of the Institute for Medicine and Biology.	
VE	In addition to the	considerably increased

In addition to the considerably increased accuracy in the determination of intensities, the following advantages will result from the device

 a. Determination of intensities can be performed by non-expert, auxiltary personnel;

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- b. Duration of the evaluation of an X-ray picture will be reduced by about eighty percent.
- 5. The complete device, including the evaluation device, is supposed to be in operating order by the end of 1954.

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